


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/767,499	NIGHTAWITZ ET AL.	
	Examiner	Art Unit	
	Devin Hanan	3745	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
415	163			415	1					
INTERNATIONAL CLASSIFICATION										
F	0	3	B	1/04						
				/						
				/						
				/						
				/						
<i>Devin Hanan</i> 1/18/06 Devin Hanan 1/18/2006 (Assistant Examiner) (Date)				<i>Edward K. Look</i> 1/21/06 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)				Total Claims Allowed: 52		
<i>H. Conner</i> 1-26-06 (Legal Instruments Examiner) (Date)								O G Print Claim(s) 1	O G Print Fig. 3A, 3B 3	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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